


<b>Search Notes</b>  	<b>Application/Control No.</b>  10667872	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANO, TAKEHIKO
	<b>Examiner</b>  APRIL Y SHAN	<b>Art Unit</b>  2435

SEARCHED			
Class	Subclass	Date	Examiner
705	51, 54 and 59	5/7/2009	a.s.
726	27, 28 and 31	5/7/2009	a.s.

SEARCH NOTES		
Search Notes	Date	Examiner
Update text in EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	5/6/2009	a.s.
double patenting search by searching inventor's name on EAST	5/7/2009	a.s.
NPL search (Google, Goolge scholar and ACM)	5/7/2009	a.s.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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